Near-field radiative heat transfer at the nanoscale

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Radiative heat transfer between objects at different temperatures is of fundamental importance in applications such as energy conversion, thermal management, lithography, data storage, and thermal microscopy [1,2]. It was predicted long ago that when the separation between objects is smaller than the thermal wavelength, which is of the order of 10 μ m at room temperature, the radiative heat transfer can be greatly enhanced due to the contribution of evanescent waves (or photon tunneling) [3]. In recent years, different experimental studies have confirmed this long-standing theoretical prediction. However, in spite of this progress, there are still many basic open questions in the context of near-field radiative heat transfer. In this talk, I will review our recent theoretical and experiment efforts to shed new light on this fundamental problem. In particular, I will discuss the following two basic issues: (i) the enhanced near-field radiative heat transfer using polar dielectric thin films [4] and (ii) the radiative heat transfer in the extreme near-field regime when objects are separated by nanometer-size distances [5].

References

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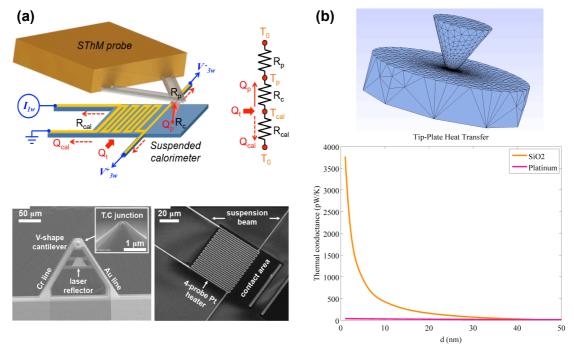
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Figure



(a) Schematic diagram of a scanning thermal microscopy probe. (b) Numerical simulation of the radiative thermal conductance between an AFM tip and a flat substrate made of both SiO_2 and platinum.